٧

Ω

600

500

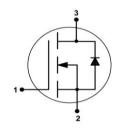
0.021



SIPMOS® Small-Signal-Transistor

Features

- n-channel
- enhancement mode
- Logic level (4.5V rated)
- dv/dt rated
- 100%lead-free; RoHS compliant
- Qualified according to AEC Q101
- Halogen-free according to IEC61249-2-21



Product Summary

 $V_{\rm DS}$

 I_{D}

 $R_{\rm DS(on),max}$







Туре	Package	Pb-free	Halogen-free	Tape and Reel Information	Marking
BSS127	PG-SOT-23	Yes	Yes	H6327: 3000PCS/reel	SIs

Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	T _A =25 °C	0.021	А
		T _A =70 °C	0.017	
Pulsed drain current	I _{D,pulse}	T _A =25 °C	0.09	
Reverse diode dv/dt	dv/dt	$I_{\rm D}$ =0.021 A, $V_{\rm DS}$ =480 V, di/dt =200 A/ μ s, $T_{\rm j,max}$ =150 °C	6	kV/μs
Gate source voltage	V_{GS}		±20	V
ESD class (JESD22-A114-HBM)			0 (<250)	
Power dissipation	P_{tot}	T _A =25 °C	0.50	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 150	°C
IEC climatic category; DIN IEC 68-1			55/150/56	



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics						
Thermal resistance, junction - minimal footprint	R_{thJA}		-	-	250	K/W

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =250 μA	600	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{DS}=V_{GS}$, $I_{D}=8 \mu A$	1.4	2.0	2.6	
Drain-source leakage current	I _{D (off)}	$V_{\rm DS} = 600 \text{ V}, V_{\rm GS} = 0 \text{ V}, $ $T_{\rm j} = 25 \text{ °C}$	1	ı	0.1	μΑ
		V _{DS} =600 V, V _{GS} =0 V, T _j =150 °C	1	ı	10	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	1	10	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =4.5 V, I _D =0.016 A	1	330	600	Ω
		V _{GS} =10 V, I _D =0.016 A	-	310	500	
Transconductance	g_{fs}	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 0.01~{\rm A}$	0.007	0.015	-	S



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	21	28	pF
Output capacitance	Coss	V_{GS} =0 V, V_{DS} =25 V, f =1 MHz	-	2.4	3]
Reverse transfer capacitance	C _{rss}		-	1.0	1.5]
Turn-on delay time	$t_{\sf d(on)}$		-	6.1	19.0	ns
Rise time	t _r	V _{DD} =300 V,	-	9.7	14.5	
Turn-off delay time	$t_{d(off)}$	$V_{\rm GS}$ =10 V, $I_{\rm D}$ =0.01 A, $R_{\rm G,ext}$ =6 Ω	-	14	21	
Fall time	t_{f}		-	115	170	
Gate Charge Characteristics						
Gate to source charge	Q _{gs}	V _{DD} =300 V, I _D =0.01 A, V _{GS} =0 to 10 V	ı	0.07	0.10	nC
Gate to drain charge	Q _{gd}		-	0.31	0.5	
Gate charge total	Qg		-	0.65	1.0	
Gate plateau voltage	V _{plateau}		-	3.56	-	V
Reverse Diode	-					
Diode continous forward current	Is	-T _A =25 °C	-	-	0.016	А
Diode pulse current	I _{S,pulse}		-	-	0.09	1
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =0.016 A, T _j =25 °C	-	0.82	1.2	V
Reverse recovery time	t _{rr}	V _R =300 V,	-	160	240	ns
Reverse recovery charge	Q _{rr}	-/ _F =0.016 A, d <i>i</i> _F /d <i>t</i> =100 A/μs	-	13.2	19.8	nC

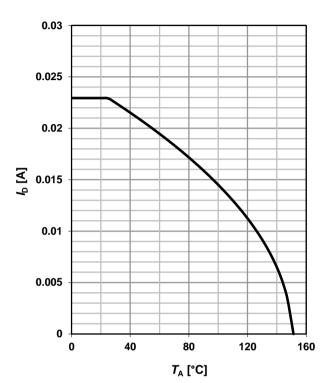


1 Power dissipation

$P_{\text{tot}} = f(T_A)$

0.6 0.5 0.4 0.2 0.1 0 40 80 120 160 T_A [°C]

2 Drain current



3 Safe operating area

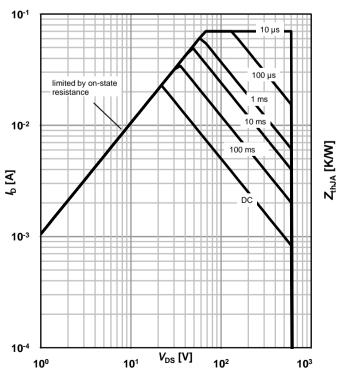
 $I_D=f(V_{DS}); T_A=25 \text{ °C}; D=0$

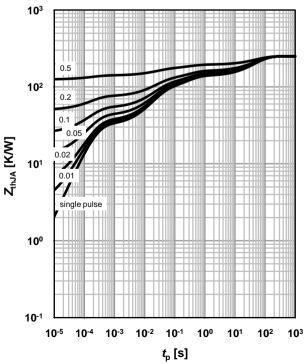
parameter: t_p

4 Max. transient thermal impedance

 $Z_{\text{thJA}} = f(t_p)$

parameter: $D=t_p/T$



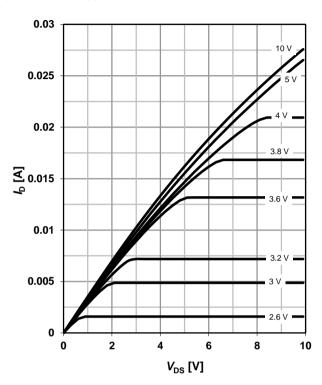




5 Typ. output characteristics

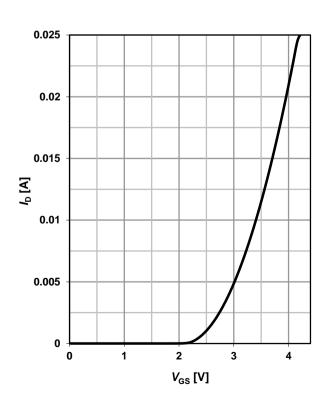
 $I_D=f(V_{DS}); T_j=25 °C$

parameter: V_{GS}



7 Typ. transfer characteristics

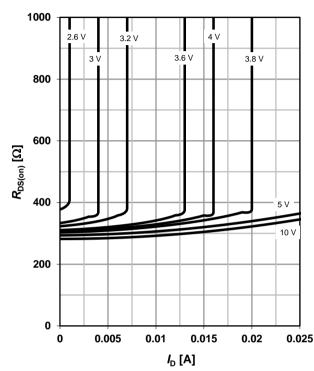
 I_{D} =f(V_{GS}); $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$



6 Typ. drain-source on resistance

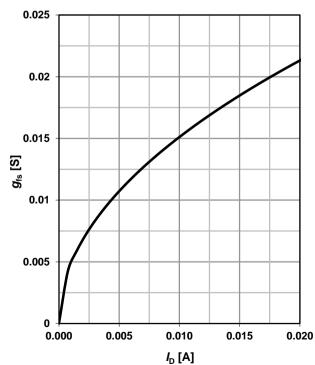
 $R_{DS(on)}=f(I_D); T_i=25 °C$

parameter: V_{GS}



8 Typ. forward transconductance

 g_{fs} =f(I_D); T_j =25 °C





9 Drain-source on-state resistance

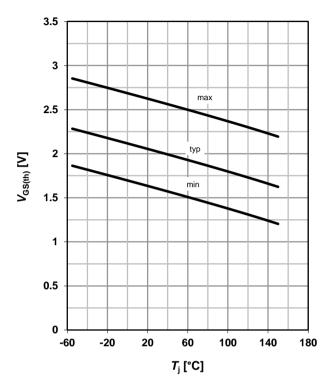
 $R_{DS(on)} = f(T_i); I_D = 0.016 \text{ A}; V_{GS} = 10 \text{ V}$

1000 900 800 700 600 $R_{\mathrm{DS(on)}}\left[\Omega\right]$ 500 400 300 200 100 -60 -20 20 60 100 140 180 *T*_j [°C]

10 Typ. gate threshold voltage

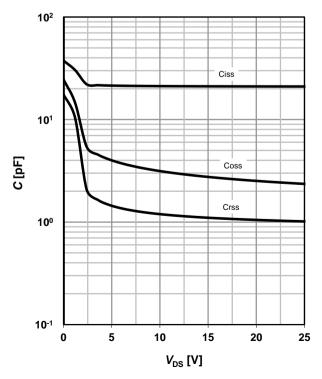
 $V_{\text{GS(th)}} = f(T_{\text{j}}); V_{\text{DS}} = V_{\text{GS}}; I_{\text{D}} = 8 \text{ }\mu\text{A}$

parameter: I_D



11 Typ. capacitances

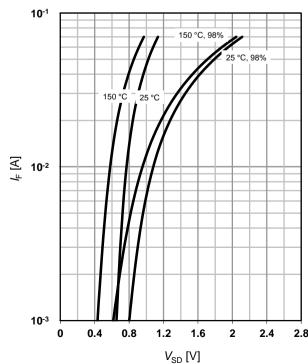
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz; T_i=25$ °C



12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$

parameter: T_i





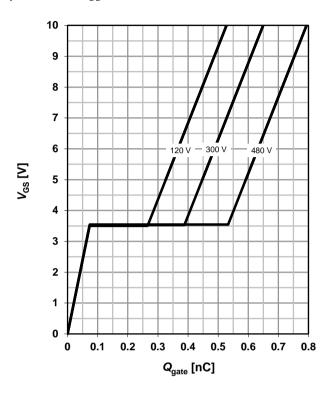
13 Typ. gate charge

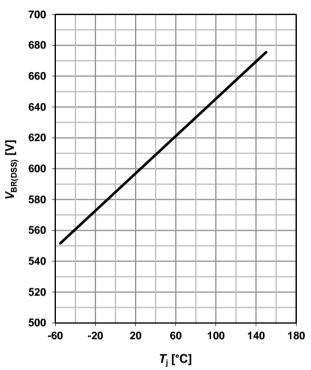
 V_{GS} =f(Q_{gate}); I_{D} =0.01 A pulsed

parameter: V_{DD}

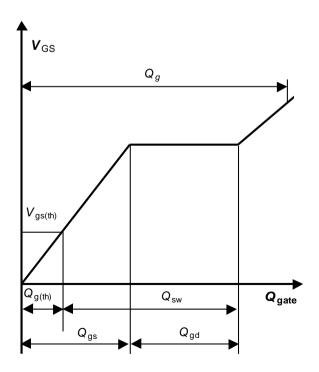
14 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=250 \mu A$





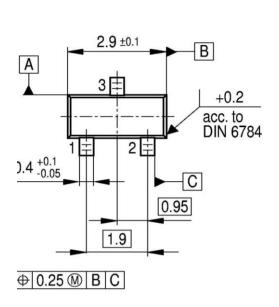
15 Gate charge waveforms

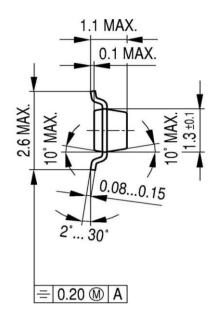




SOT-23

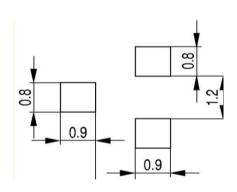
Package Outline:

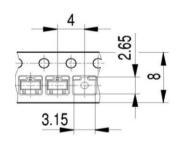


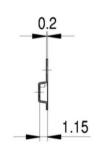


Footprint:

Packaging:









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